

# **Package Qualification Report**

Reliability By Design

### **Qualification Description:**

The information contained herein represents proof of Reliability and Performance of the Package Series listed below in accordance with the Qualification Plan and test methods referenced in Section 7.0, after exposure to a variety of environments and mechanical events that occur during installation and operational lifetime of the product. Upon conclusion of the testing the product continued to operate within specification limits, demonstrating its capability of reliable operation throughout its lifetime.

The purpose of this report is to present Qualification Test results of the referenced Package Series. The Pericom product data presented in this report qualifies the products manufactured in this package configuration, using the same bill of materials and assembled by the identified subcontractor location. The report describes the qualification test program, procedures utilized, criteria enforced (at the time of product validation), and specific result data obtained during the testing of three lots of semiconductors. The three lots consist of an equal number of units from different date codes, from the same production line and SubContractor to ensure manufacturing repeatability.

### Lot Background Information:

Qual Part Number:	Eng part number
Supplier (Code):	UTL (Z)
Pkg Type - Code:	SOIC-28 (S28)
Outline Drawing:	PD-1008
By Extension Pkg:	S20

Qual Test Date: Die Attach Material: Wire Size & Material: Mold Compound: Leadframe Material: Lead Finish: Date Codes:

Feb-2004 update Feb-2012
Ablestik 2200D
1.3 mil Gold
G600
Copper
100% Matte Sn

### Pericom's Qualification Test Results:

Stress Test	Test Procedure	Test Conditions	Duration	# of Lots	Samples per Lot	Results Pass/Fail
Preconditioning	JESD22-A113	MSL1	NA	3	255	255 / 0
CSAM	J-STD-020	No delamination of Die Top, Wire bond, Down bond areas	NA	3	22	22 / 0
Precon Autoclave	JESD22-A1	121°C, RH 100%, 29.7psig, 0V	168 hrs	3	85	85 / 0
PreCon Temp Cycle	JESD22-A104	-65°C to +150°C 500 Cycles	100 cycles	3	85	85 / 0
		-65°C to +150°C 500 Cycles	500 cycles	3	85	85 / 0
Physical Dimension	JESD22-B100	Per Datasheeet	NA	3	5	5/0
External Visual Insp	JESD22-B101	NA	NA	3	5	5/0
Terminal Strength	JESD22-B105	90° Bends, 2 bend min.	NA	3	5	5/0
Solderability	J-STD-020 JESD22-B102	Pb-Free Solder Dip 245°C	NA	3	5	5/0

### **Qualificaton by Extension Information:**

Where a product of interest is not sampled during this period, it is valid to use the reliability data of the particular process technology or package type family to which the part belongs. All parts within the same family are designed to the same rules, and manufacturing is controlled by SPC. Within a product family, a device can only be fabricated on one process technology/ option, and only assembled on one package type process.

If there are any questions about this qualification, please contact Quality Support at:

customerquestion@pericom.com



Date:	Feb-2004 update Feb-2012
PKG Type & Code:	SOIC-28 (S28)
Assembler-Code:	UTL (Z)
Qual Device:	Eng part number

## By extension: Pericom active devices using the Fab/Process at the time of the Qualification:

PI49FCT38072CSE		
PI49FCT38072CSEX		
PI49FCT3807ASE		
PI49FCT3807ASEX		
PI49FCT3807CSE		
PI49FCT3807CSEX		
PI49FCT3807DSE		
PI49FCT3807DSEX		
PI49FCT805ATSE		
PI49FCT805ATSEX		
PI49FCT807CTSE		
PI49FCT807CTSEX		
PI74FCT2245TSE		
PI74FCT2245TSEX		
PI74FCT244ATSE		
PI74FCT244ATSEX		
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PI74FCT245TSEX		
PI74FCT2541ATSE		
PI74FCT2541ATSEX		
PI74FCT573ATSE		
PI74FCT573ATSEX		



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The purpose of this report is to present Qualification Test results of the referenced Package Series. The Pericom product data presented in this report qualifies the products manufactured in this package configuration, using the same bill of materials and assembled by the identified subcontractor location. The report describes the qualification test program, procedures utilized, criteria enforced (at the time of product validation), and specific result data obtained during the testing of three lots of semiconductors. The three lots consist of an equal number of units from different date codes, from the same production line and SubContractor to ensure manufacturing repeatability.

#### Lot Background Information:

Qual Vehicle:	PI74FCT254ATSE
Supplier (Code):	SPEL (X)
Pkg Type - Code:	SOIC-20 (S20)
Outline Drawing:	PD-1006
By Extension Pkg:	none

Qual Test Date: Die Attach Material: Wire Size & Material: Mold Compound: Leadframe Material: Lead Finish: Date Codes:

:	Dec-2010
l:	CRM 1076
l:	1.0 mil Gold
l:	EME G600
l:	A194 Copper
ı:	100% Matte Sn
s:	1027XG

### Pericom's Qualification Test Results:

Stress Test	Test Procedure	Test Conditions	Duration	# of Lots	Samples per Lot	Results Pass/Fail
Preconditioning	JESD22-A113	MSL1	NA	1	100	100 / 0
CSAM	J-STD-020	No delamination of Die Top, Wire bond, Down bond areas	NA	1	11	11/0
PreCon UHAST	JESD22-A118	130°C, RH 85%, 33.3 psia, 0V	96 hrs	1	45	45 / 0
PreCon Temp Cycle	JESD22-A104	-65°C to +150°C 500 Cycles	100 cycles	1	45	45 / 0
		-65°C to +150°C 500 Cycles	500 cycles	1	45	45 / 0
HTSL (no PreCon)	JESD22-A103	1000hrs, 0V, 150°C	500 hrs	1	45	45 / 0
		1000hrs, 0V, 150°C	1000 hrs	1	45	45 / 0
Physical Dimension	JESD22-B100	Per Datasheeet	NA	1	5	5 / 0
External Visual Insp	JESD22-B101	NA	NA	1	5	5/0
Terminal Strength	JESD22-B105	90° Bends, 2 bend min.	NA	1	5	5/0
Solderability	J-STD-020 JESD22-B102	Pb-Free Solder Dip 245°C	NA	1	5	5/0

#### **Qualificaton by Extension Information:**

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customerguestion@pericom.com



Date:	Dec-2010
PKG Type & Code:	SOIC-20 (S20)
Assembler-Code:	SPEL (X)
Qual Device:	PI74FCT254ATSE

## By extension: Pericom active devices using the Fab/Process at the time of the Qualification:

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